

MOS FIELD EFFECT TRANSISTOR 2SK3386

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

The 2SK3386 is N-Channel MOS Field Effect Transistor designed for high current switching applications.

FEATURES

• Low On-state Resistance

 $R_{DS(on)1} = 21 \text{ m}\Omega \text{ MAX. (Vgs} = 10 \text{ V, ID} = 17 \text{ A)}$

 $R_{DS(on)2} = 36 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 4.0 \text{ V, I}_D = 17 \text{ A)}$

- Low Ciss : Ciss = 2100 pF TYP.
- Built-in Gate Protection Diode
- TO-251/TO-252 package

ORDERING INFORMATION

PART NUMBER	PACKAGE		
2SK3386	TO-251		
2SK3386-Z	TO-252		

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

	Drain to Source Voltage	VDSS	60	V
	Gate to Source Voltage	Vgss	±20	V
	Drain Current (DC)	ID(DC)	±34	Α
*	Drain Current (Pulse) Note1	D(pulse)	±120	Α
	Total Power Dissipation (Tc = 25°C)	Рт	40	W
	Total Power Dissipation (T _A = 25°C)	Рт	1.0	W
	Channel Temperature	Tch	150	°C
	Storage Temperature	Tstg	-55 to +150	°C
	Single Avalanche Current Note2	las	28	Α
	Single Avalanche Energy Note2	Eas	78	mJ

(TO-251)



(TO-252)



Notes 1. PW \leq 10 μ s, Duty cycle \leq 1%

2. Starting T_{ch} = 25°C, V_{DD} = 30 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V

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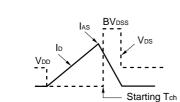


ELECTRICAL CHARACTERISTICS (TA = 25°C)

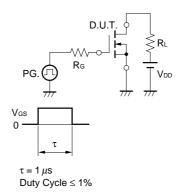
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 60 V, V _{GS} = 0 V			10	μΑ
Gate Leakage Current	Igss	V _{GS} = ±20 V, V _{DS} = 0 V			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	y fs	V _{DS} = 10 V, I _D = 17 A	10	19		S
Drain to Source On-state Resistance	RDS(on)1	V _{GS} = 10 V, I _D = 17 A		17	21	mΩ
	RDS(on)2	V _{GS} = 4.0 V, I _D = 17 A		25	36	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		2100		pF
Output Capacitance	Coss	V _{GS} = 0 V		340		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		170		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 30 V, I _D = 17 A		32		ns
Rise Time	tr	V _{GS(on)} = 10 V		310		ns
Turn-off Delay Time	td(off)	R _G = 10 Ω		98		ns
Fall Time	tf			100		ns
Total Gate Charge	Q _G	V _{DD} = 48 V		39		nC
Gate to Source Charge	Qgs	V _{GS(on)} = 10 V		7.0		nC
Gate to Drain Charge	Q _{GD}	I _D = 34 A		12		nC
Body Diode Forward Voltage	V _{F(S-D)}	I _F = 34 A, V _{GS} = 0 V		0.87		V
Reverse Recovery Time	trr	I _F = 34 A, V _{GS} = 0 V		46		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		84		nC

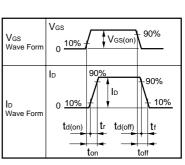
TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c|c} D.U.T. \\ \hline PG. \\ \hline \\ V_{GS} = 20 \text{ V} \rightarrow 0 \text{ V} \end{array}$



TEST CIRCUIT 2 SWITCHING TIME

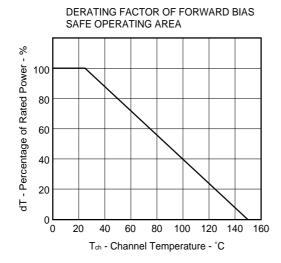


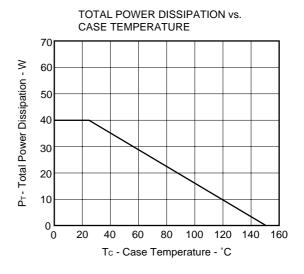


TEST CIRCUIT 3 GATE CHARGE

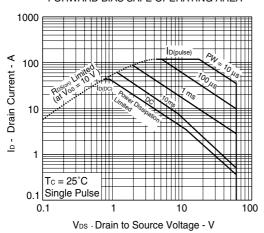


* TYPICAL CHARACTERISTICS (TA = 25°C)

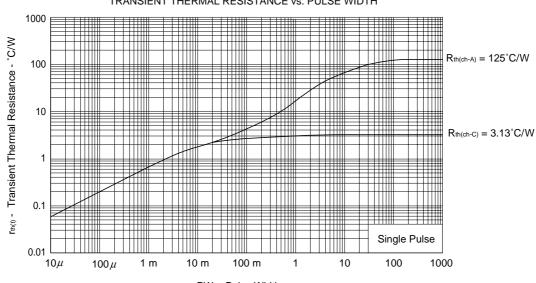




FORWARD BIAS SAFE OPERATING AREA



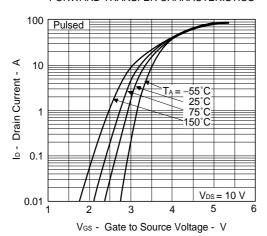
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



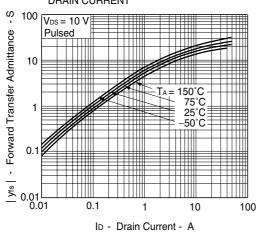
PW - Pulse Width - s

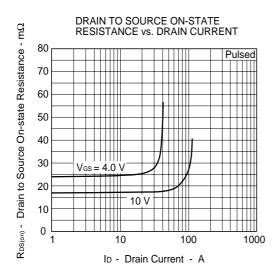
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FORWARD TRANSFER CHARACTERISTICS

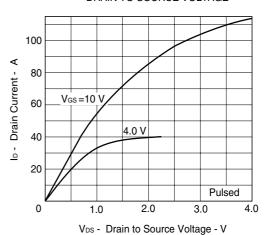


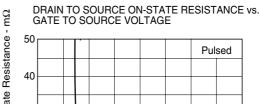
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

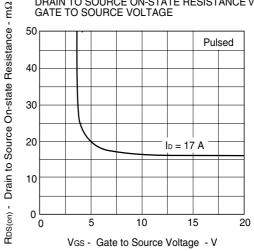




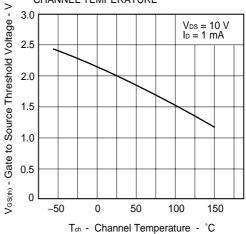
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



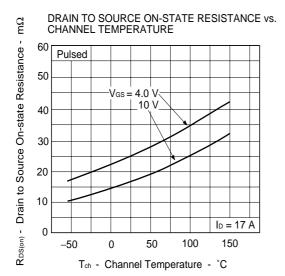


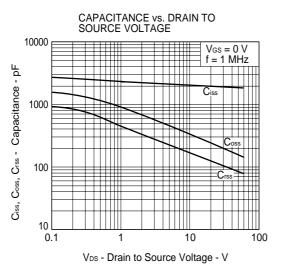


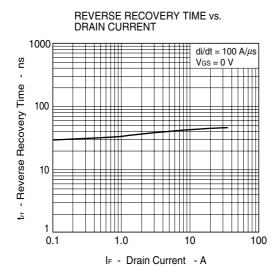
GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

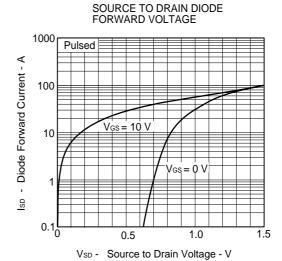


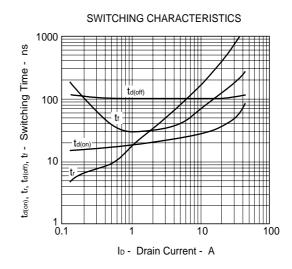


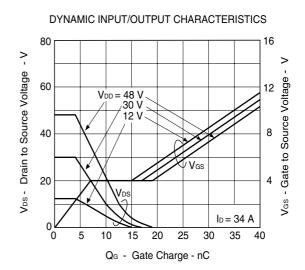


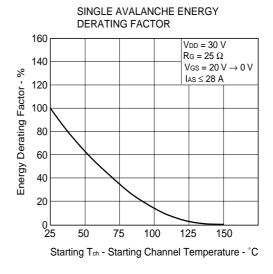








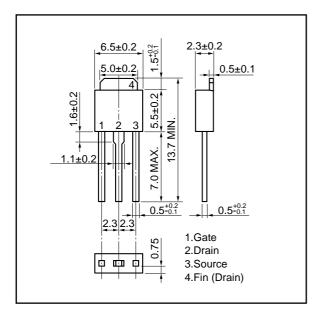




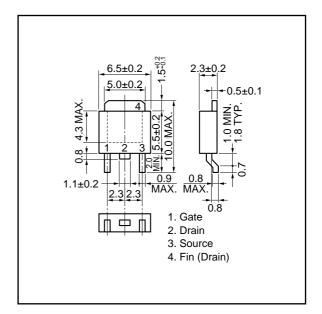


PACKAGE DRAWINGS (Unit: mm)

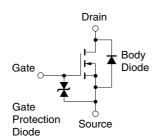
1) TO-251 (MP-3)



2) TO-252 (MP-3Z)



EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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